

# AONS62606

## 60V N-Channel MOSFET

## **General Description**

- Trench Power AlphaSGT<sup>™</sup> technology
- Low R<sub>DS(ON)</sub>
- Logic Level Driving
- Excellent Q<sub>g</sub> x R<sub>DS(ON)</sub> Product (FOM)
- Pb-Free lead Plating, RoHS 2.0 and Halogen-Free Compliant

## **Applications**

• High Frequency Switching and Synchronous Rectification

**Orderable Part Number** 

## **Product Summary**

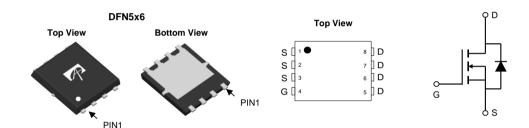
 $\begin{array}{lll} V_{DS} & 60V \\ I_{D} \; (at \; V_{GS} \! = \! 10V) & 195A \\ R_{DS(ON)} \; (at \; V_{GS} \! = \! 10V) & < 2.7 m\Omega \\ R_{DS(ON)} \; (at \; V_{GS} \! = \! 4.5V) & < 3.7 m\Omega \end{array}$ 

100% UIS Tested 100% Rg Tested

Form



**Minimum Order Quantity** 



Package Type

AONS62606		DFN 5x6	Tape & Reel	3000	
Absolute Maximum	Ratings T <sub>A</sub> =25°C unle	ess otherwise not	red		
Parameter		Symbol	Maximum	Units	
Drain-Source Voltage		$V_{DS}$	60	V	
Gate-Source Voltage		$V_{GS}$	±20	V	
Continuous Drain Current	T <sub>C</sub> =25°C		195		
	T <sub>C</sub> =100°C	I <sub>D</sub>	123	A	
Pulsed Drain Current <sup>C</sup>		I <sub>DM</sub>	315		
Continuous Drain	T <sub>A</sub> =25°C		35	Δ.	
Current	T <sub>A</sub> =70°C	IDSM	28	A	
Avalanche Current <sup>C</sup>		I <sub>AS</sub>	60	А	
Avalanche energy	L=0.1mH <sup>C</sup>	E <sub>AS</sub>	180	mJ	
	T <sub>C</sub> =25°C	В	192	W	
Power Dissipation <sup>B</sup>	T <sub>C</sub> =100°C	P <sub>D</sub>	76	VV	
	T <sub>A</sub> =25°C	В	6.2	10/	
Power Dissipation A	T <sub>A</sub> =70°C	P <sub>DSM</sub>	4	W	
Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>STG</sub>	-55 to 150	°C	

Thermal Characteristics								
Parameter		Symbol	Тур	Max	Units			
Maximum Junction-to-Ambient A	t ≤ 10s	$R_{\theta,JA}$	15	20	°C/W			
Maximum Junction-to-Ambient AD	Steady-State		40	50	°C/W			
Maximum Junction-to-Case Steady-State		$R_{\theta JC}$	0.5	0.65	°C/W			



#### Electrical Characteristics (T<sub>.I</sub>=25°C unless otherwise noted)

Symbol	Parameter	Conditions		Min	Тур	Max	Units		
STATIC PARAMETERS									
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	I <sub>D</sub> =250μA, V <sub>GS</sub> =0V		60			V		
lana	Zero Gate Voltage Drain Current	V <sub>DS</sub> =60V, V <sub>GS</sub> =0V				1	μA		
I <sub>DSS</sub>	Zero Gate Voltage Drain Current		T <sub>J</sub> =55°C			5	μΛ		
I <sub>GSS</sub>	Gate-Body leakage current	$V_{DS}$ =0V, $V_{GS}$ =±20V				±100	nA		
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS,}I_{D}=250\mu A$		1.1	1.6	2.1	V		
	Static Drain-Source On-Resistance	$V_{GS}$ =10V, $I_{D}$ =20A			2.2	2.7	mΩ		
$R_{DS(ON)}$			T <sub>J</sub> =125°C		3.6	4.4	11177		
		$V_{GS}$ =4.5V, $I_D$ =20A			2.9	3.7	mΩ		
g <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> =5V, I <sub>D</sub> =20A			100		S		
$V_{SD}$	Diode Forward Voltage	I <sub>S</sub> =1A, V <sub>GS</sub> =0V			0.7	1	V		
Is	Maximum Body-Diode Continuous Curr	ode Continuous Current				195	Α		
DYNAMIC	PARAMETERS								
C <sub>iss</sub>	Input Capacitance	V <sub>GS</sub> =0V, V <sub>DS</sub> =30V, f=1MHz			4150		pF		
C <sub>oss</sub>	Output Capacitance				1050		pF		
$C_{rss}$	Reverse Transfer Capacitance				75		рF		
$R_g$	Gate resistance	f=1MHz		0.4	0.8	1.2	Ω		
SWITCHI	NG PARAMETERS								
Q <sub>g</sub> (10V)	Total Gate Charge	-V <sub>GS</sub> =10V, V <sub>DS</sub> =30V, I <sub>D</sub> =20A			65	92	nC		
Q <sub>g</sub> (4.5V)	Total Gate Charge				31	44	nC		
$Q_{gs}$	Gate Source Charge				8.5		nC		
$Q_{gd}$	Gate Drain Charge				10		nC		
Q <sub>oss</sub>	Output Charge	V <sub>GS</sub> =0V, V <sub>DS</sub> =30V			52		nC		
t <sub>D(on)</sub>	Turn-On DelayTime				9		ns		
t <sub>r</sub>	Turn-On Rise Time	$V_{GS}$ =10V, $V_{DS}$ =30V, $R_L$ =1.5 $\Omega$ , $R_{GEN}$ =3 $\Omega$			6		ns		
t <sub>D(off)</sub>	Turn-Off DelayTime				56		ns		
t <sub>f</sub>	Turn-Off Fall Time				11		ns		
t <sub>rr</sub>	Body Diode Reverse Recovery Time	I <sub>F</sub> =20A, di/dt=500A/μs			26		ns		
$Q_{rr}$	Body Diode Reverse Recovery Charge	I <sub>F</sub> =20A, di/dt=500A/μs			107		nC		

A. The value of  $R_{BJA}$  is measured with the device mounted on  $1in^2$  FR-4 board with 2oz. Copper, in a still air environment with  $T_A$  =25° C. The Power dissipation  $P_{DSM}$  is based on  $R_{BJA}$  t≤ 10s and the maximum allowed junction temperature of 150° C. The value in any given application depends on the user's specific board design.

APPLICATIONS OR USES AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS ARE NOT AUTHORIZED. AOS DOES NOT ASSUME ANY LIABILITY ARISING OUT OF SUCH APPLICATIONS OR USES OF ITS PRODUCTS. AOS RESERVES THE RIGHT TO MAKE CHANGES TO PRODUCT SPECIFICATIONS WITHOUT NOTICE. IT IS THE RESPONSIBILITY OF THE CUSTOMER TO EVALUATE SUITABILITY OF THE PRODUCT FOR THEIR INTENDED APPLICATION. CUSTOMER SHALL COMPLY WITH APPLICABLE LEGAL REQUIREMENTS, INCLUDING ALL APPLICABLE EXPORT CONTROL RULES, REGULATIONS AND LIMITATIONS.

AOS' products are provided subject to AOS' terms and conditions of sale which are set forth at: <a href="http://www.aosmd.com/terms">http://www.aosmd.com/terms</a> and conditions of sale

B. The power dissipation  $P_D$  is based on  $T_{J(MAX)}$ =150° C, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Single pulse width limited by junction temperature  $\rm T_{J(MAX)}\!\!=\!\!150^\circ\,$  C.

D. The  $R_{\theta JA}$  is the sum of the thermal impedance from junction to case  $R_{\theta JC}$  and case to ambient.

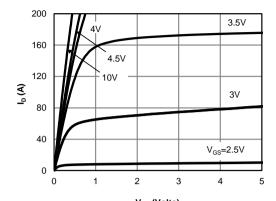
E. The static characteristics in Figures 1 to 6 are obtained using <300  $\mu$ s pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of T<sub>J(MAX)</sub>=150° C. The SOA curve provides a single pulse rating.

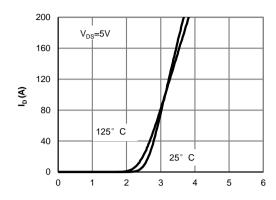
G. These tests are performed with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with T<sub>A</sub>=25° C.



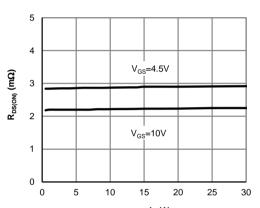
#### TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS



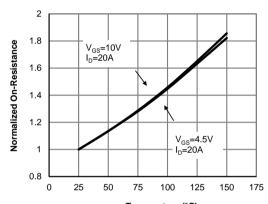
 $V_{\rm DS}$  (Volts) Figure 1: On-Region Characteristics (Note E)



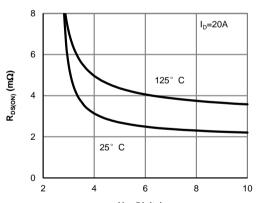
V<sub>GS</sub> (Volts)
Figure 2: Transfer Characteristics (Note E)



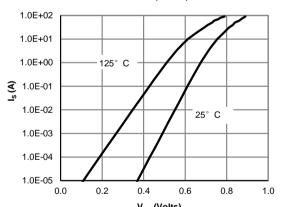
 $\label{eq:local_local} I_{D}\left(\mathbf{A}\right)$  Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)



Temperature (°C)
Figure 4: On-Resistance vs. Junction Temperature (Note E)



V<sub>GS</sub> (Volts)
Figure 5: On-Resistance vs. Gate-Source Voltage
(Note E)



V<sub>SD</sub> (Volts) Figure 6: Body-Diode Characteristics (Note E)

100

10



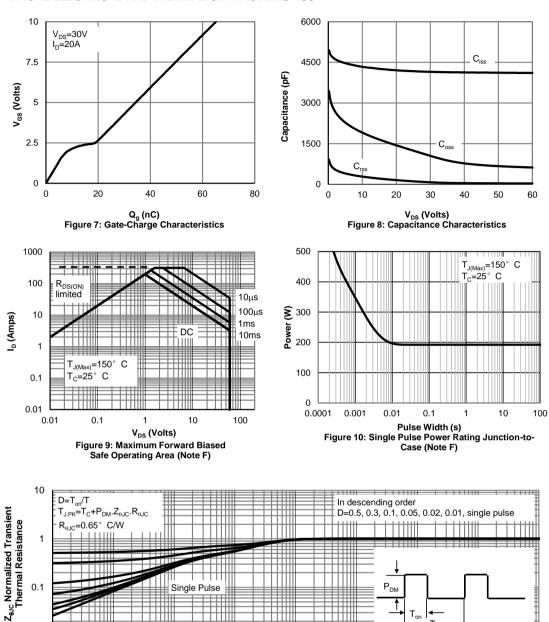
0.01

1E-06

1E-05

0.0001

#### TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS



Pulse Width (s)
Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

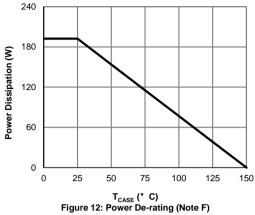
0.01

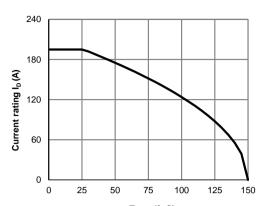
0.1

0.001

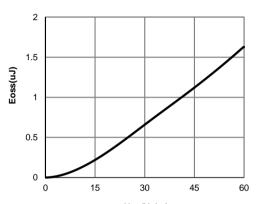


#### TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS





T<sub>CASE</sub> (° C)
Figure 13: Current De-rating (Note F)



V<sub>DS</sub> (Volts) Figure 14: Coss stored Energy

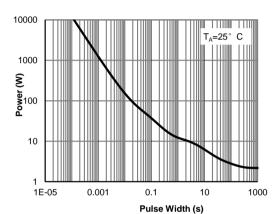
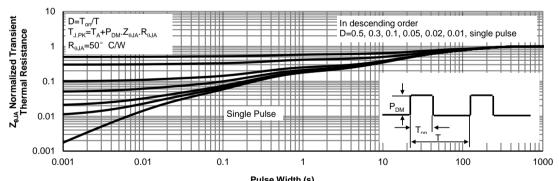


Figure 15: Single Pulse Power Rating Junction-to-Ambient (Note G)



Pulse Width (s)
Figure 16: Normalized Maximum Transient Thermal Impedance (Note G)

Figure A: Gate Charge Test Circuit & Waveforms

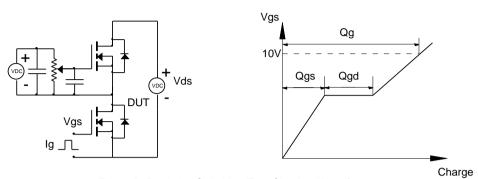


Figure B: Resistive Switching Test Circuit & Waveforms

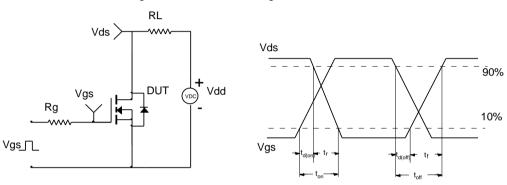


Figure C: Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

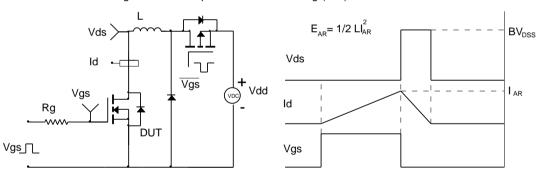


Figure D: Diode Recovery Test Circuit & Waveforms

